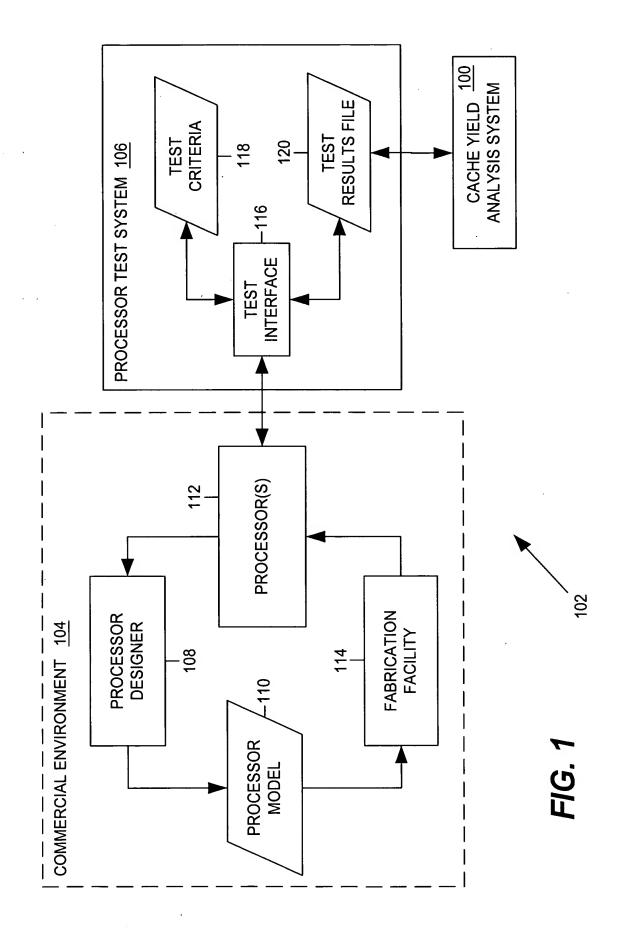
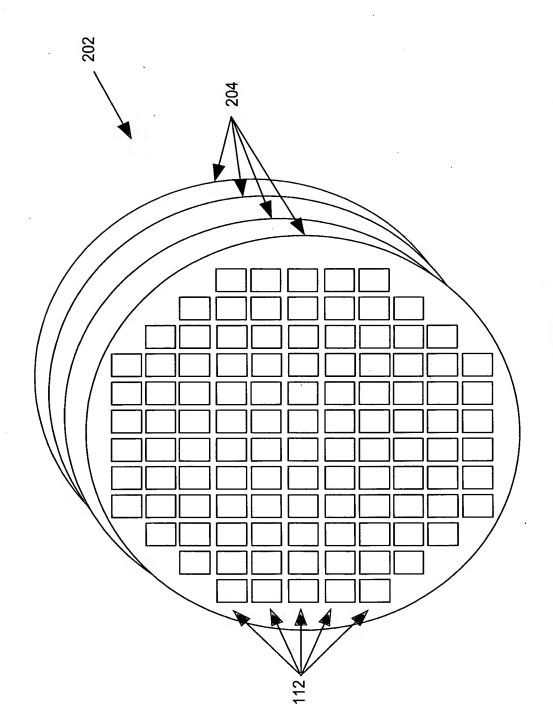
Inventor: Elias Gedamu Title: Cache Testing for a Processor Design HP Docket No.: 200209681-1 1 / 7

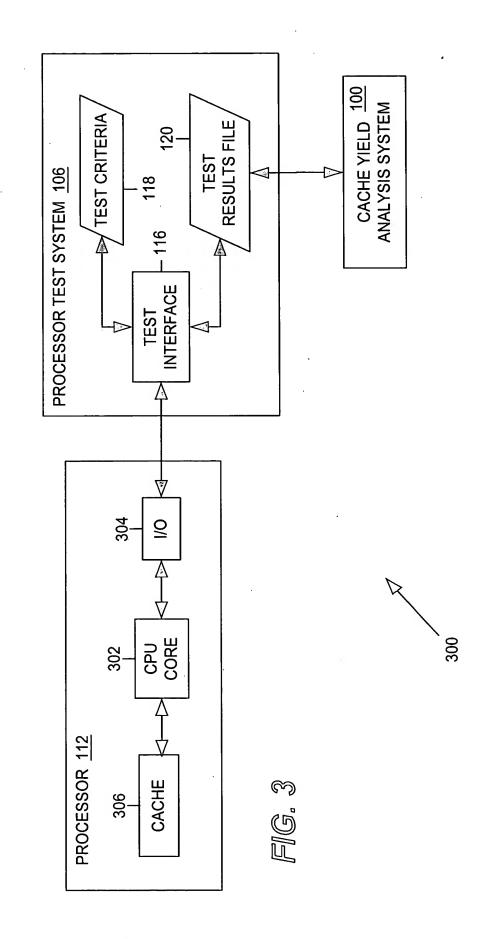


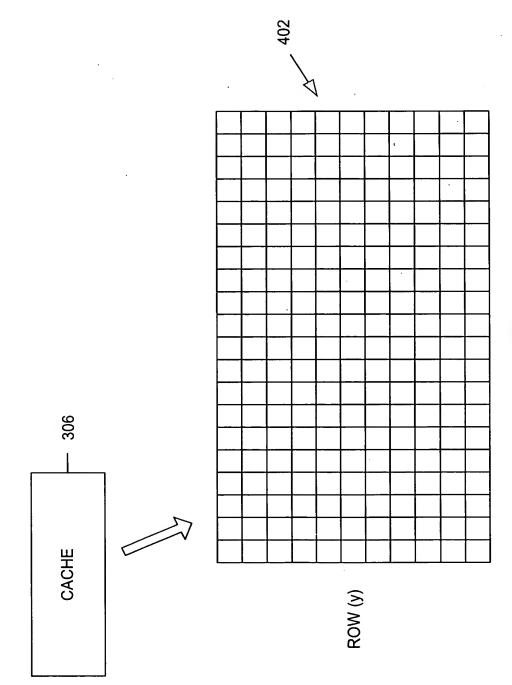
Inventor: Elias Gedamu Title: Cache Testing for a Processor Design HP Docket No.: 200209681-1 2 / 7



FIG

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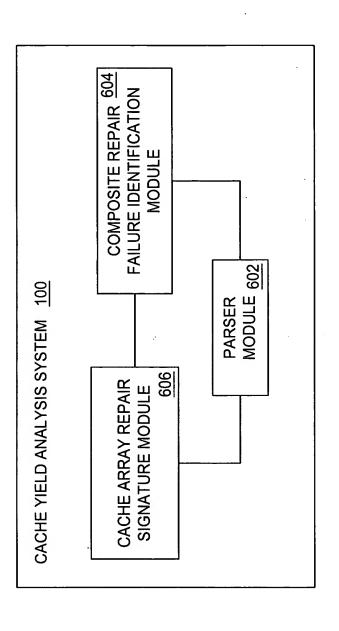
Inventor: Elias Gedamu
Title: Cache Testing for a Processor Design
HP Docket No.: 200209681-1
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COLUMN (y)

506 DEVELOP A CACHE ARRAY REPAIR SIGNATURE BASED ON IDENTIFIED LOCATIONS AND/OR IDENTIFY LOCATIONS (e.g., COLUMN, ROW) IN CACHE ARRAY(S) THAT FAIL COMPOSITE CORRESPONDING COMPOSITE REPAIR TEST - 504 Inventor: Elias Gedamu Title: Cache Testing for a Processor Design HP Docket No.: 200209681-1 5 / 7 REPAIR TEST(S) RESULTS FILE **RESULTS FILE** PARSE TEST **OPEN TEST** 502 — **208** –

FIG. 5

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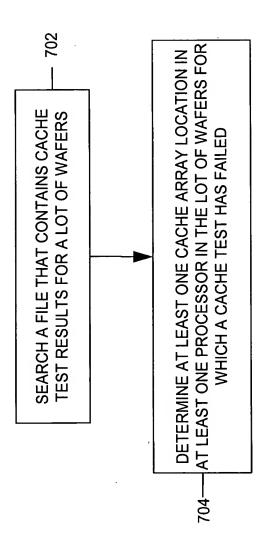


FIG. 7